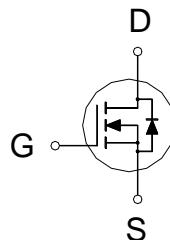


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	100V
R _{DSON} (MAX.)	22mΩ
I _D	36A



UIS, R_G 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current	T _C = 25 °C	I _D	36	A
	T _C = 100 °C		22	
Pulsed Drain Current ¹		I _{DM}	140	
Avalanche Current		I _{AS}	30	
Avalanche Energy	L = 0.1mH, ID=30A, RG=25Ω	E _{AS}	45	mJ
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	22.5	
Power Dissipation	T _C = 25 °C	P _D	50	W
	T _C = 100 °C		20	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	2.5	62	°C / W
Junction-to-Ambient	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

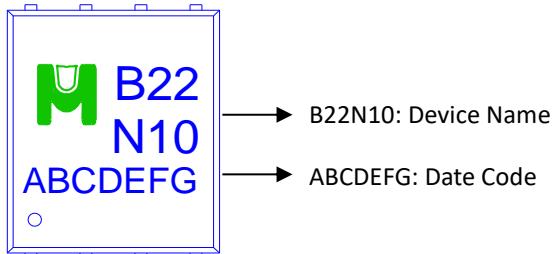
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.0	2.0	3.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 70\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 10\text{V}$	36			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 17\text{A}$		17	22	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 10\text{A}$		21	26	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 17\text{A}$		32		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 50\text{V}, f = 1\text{MHz}$		1503		pF
Output Capacitance	C_{oss}			109		
Reverse Transfer Capacitance	C_{rss}			6		
Gate Resistance	R_g	$V_{\text{GS}} = 15\text{mV}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.6		Ω
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = 50\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 17\text{A}$		21		nC
Gate-Source Charge ^{1,2}	Q_{gs}			10.5		
Gate-Drain Charge ^{1,2}	Q_{gd}			5.6		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 50\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		3.4		nS
Rise Time ^{1,2}	t_r			7		
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			5		
Fall Time ^{1,2}	t_f			17		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_s				36	A
Pulsed Current ³	I_{SM}				140	
Forward Voltage ¹	V_{SD}	$I_F = 17\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 17\text{A}, dI_F/dt = 500\text{A}/\mu\text{s}$		21		nS
Reverse Recovery Charge	Q_{rr}			92		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

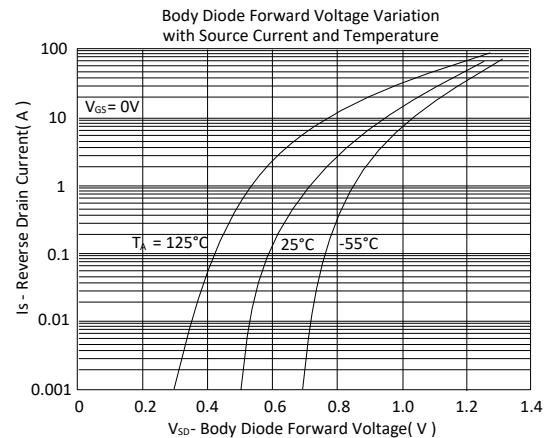
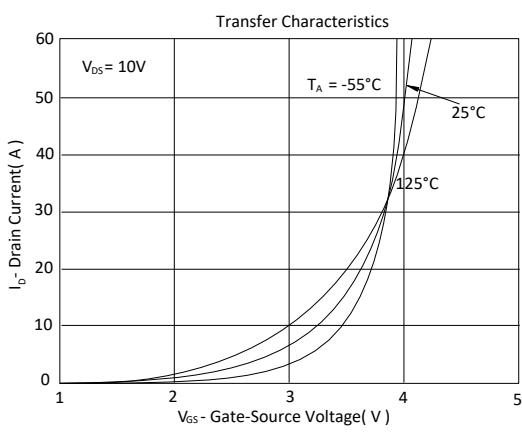
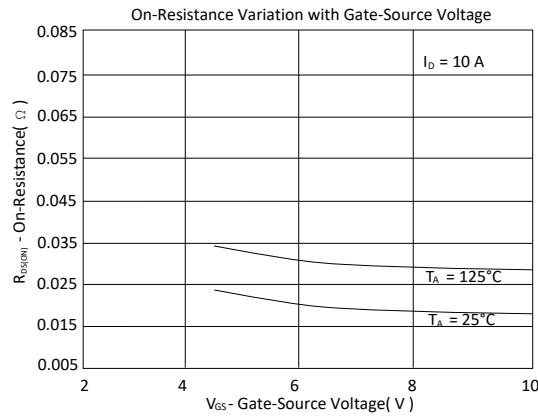
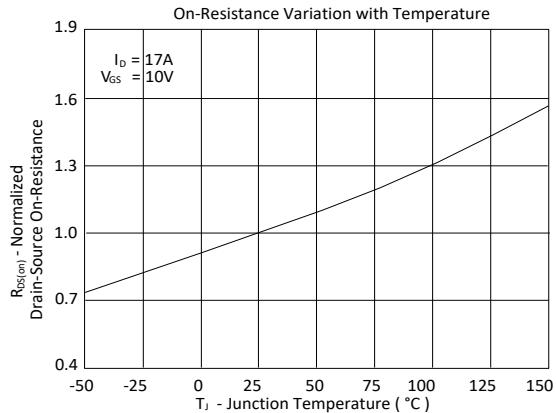
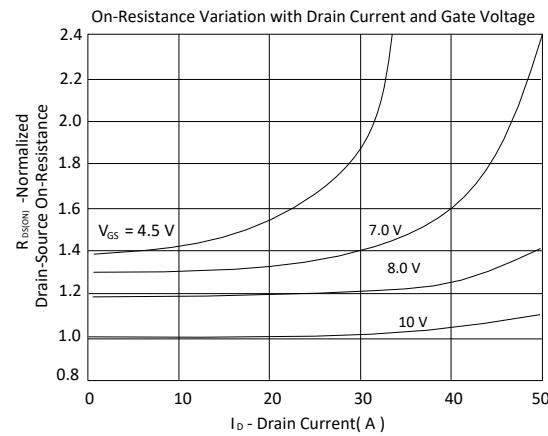
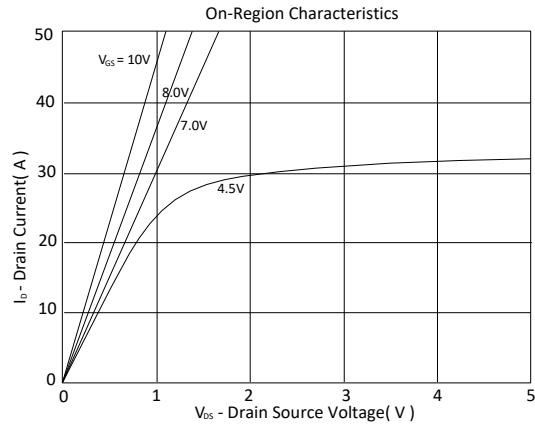
³Pulse width limited by maximum junction temperature.

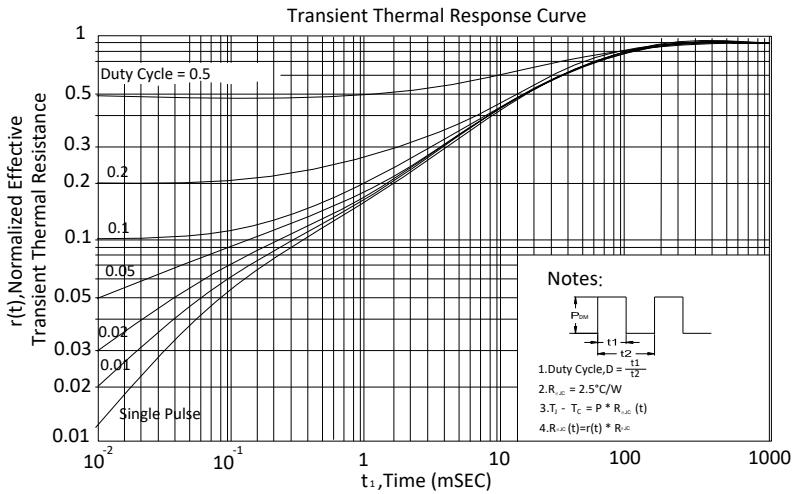
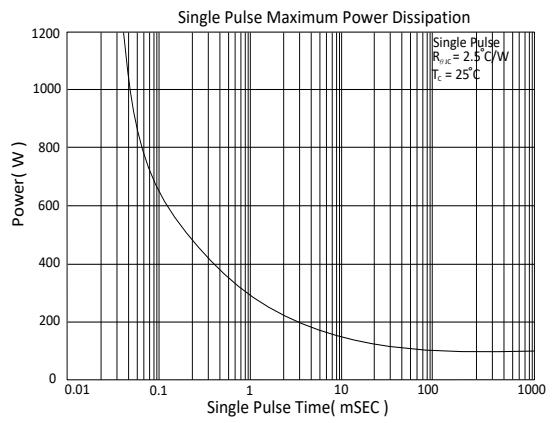
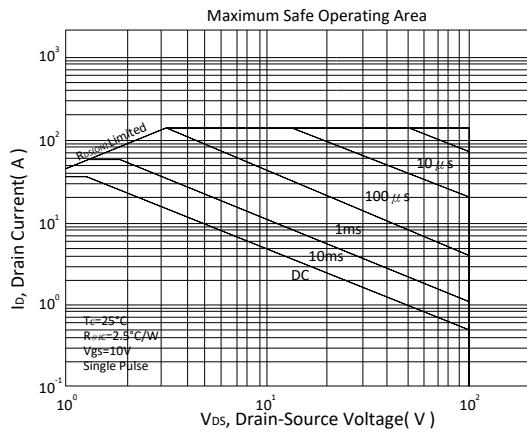
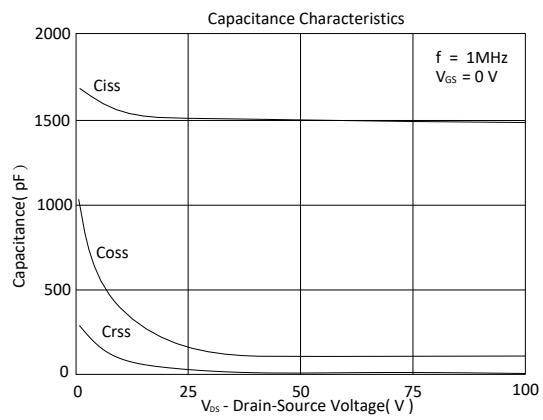
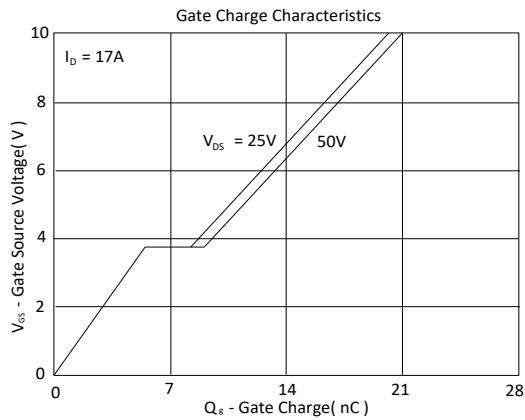
Ordering & Marking Information:

Device Name: EMB22N10H for EDFN 5 x 6

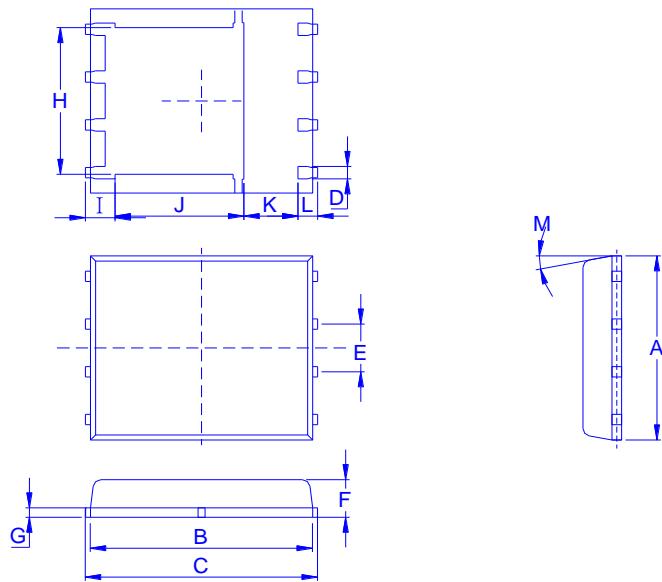


TYPICAL CHARACTERISTICS





Outline Drawing



Dimension in mm

Dimension	A	B	C	D	E	F	G	H	I	J	K	L	M
Min.	4.80	5.50	5.90	0.3		0.85	0.15	3.67	0.41	3.00	0.94	0.45	0°
Typ.					1.27								
Max.	5.30	5.90	6.15	0.51		1.20	0.30	4.54	0.85	3.92	1.7	0.71	12°

Recommended minimum pads

